

# **OptiMOS**<sup>™</sup> Small-Signal-Transistor

## **Features**

- N-channel
- Enhancement mode
- Logic level (4.5V rated)
- Avalanche rated
- Qualified according to AEC Q101
- 100% lead-free; RoHS compliant, Halogen free

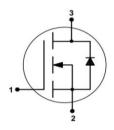




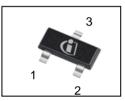


# **Product Summary**

V <sub>DS</sub>	100	V	
$R_{\rm DS(on),max}$ $V_{\rm GS}$ =10 V		6	Ω
	V <sub>GS</sub> =4.5 V	10	
I <sub>D</sub>	0.19	Α	



## PG-SOT23



Туре	Package	Tape and Reel Information	Marking	Halogon Free	Packing
BSS123N	SOT23	H6327: 3000 pcs/ reel	SAs	Yes	Non dry

# **Maximum ratings,** at $T_i$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	ID	T <sub>A</sub> =25 °C	0.19	А
		T <sub>A</sub> =70 °C	0.15	
Pulsed drain current	I <sub>D,pulse</sub>	T <sub>A</sub> =25 °C	0.77	
Avalanche energy, single pulse	E <sub>AS</sub>	$I_{\rm D}$ =0.19 A, $R_{\rm GS}$ =25 $\Omega$	2.0	mJ
Reverse diode d $v$ /d $t$	dv/dt	I <sub>D</sub> =0.19 A, V <sub>DS</sub> =80 V, d <i>i</i> /d <i>t</i> =200 A/μs, T <sub>j,max</sub> =150 °C	6	kV/μs
Gate source voltage	$V_{GS}$		±20	V
Power dissipation <sup>1)</sup>	P <sub>tot</sub>	T <sub>A</sub> =25 °C	0.5	W
Operating and storage temperature	$T_{\rm j},~T_{\rm stg}$		-55 150	°C
ESD Class		JESD22-A114 -HBM	0 (<250V)	
Soldering Temperature			260 °C	
IEC climatic category; DIN IEC 68-1			55/150/56	



Parameter	Symbol Cond	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics		•				
Thermal resistance, junction - ambient	$R_{thJA}$	minimal footprint 1)	-	-	250	K/W

# **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

## Static characteristics

Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0 V, I <sub>D</sub> =250 μA	100	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}$ =Vgs V, $I_{\rm D}$ =13 $\mu {\rm A}$	0.8	1.4	1.8	
Drain-source leakage current	I <sub>DSS</sub>	$V_{\rm DS}$ =100 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	1	ı	0.01	μА
		V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =150 °C	-	-	5	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	-	10	nA
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	V <sub>GS</sub> =4.5 V, I <sub>D</sub> =0.15 A	1	2.7	10	Ω
		V <sub>GS</sub> =10 V, I <sub>D</sub> =0.19 A	1	2.4	6	
Transconductance	$g_{fs}$	$ V_{\rm DS}  > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 0.15~{\rm A}$		0.41	-	S

 $<sup>^{1)}</sup>$  Performed on 40mm $^2$  FR4 PCB. The traces are 1mm wide, 70 $\mu$ m thick and 20mm long; they are present on both sides of the PCB



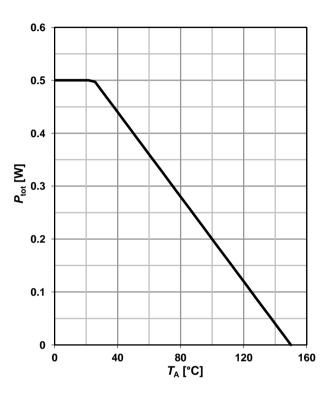
Parameter	Symbol	Symbol Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	15.7	20.9	pF
Output capacitance	Coss	V <sub>GS</sub> =0 V, V <sub>DS</sub> =25 V, f=1 MHz	-	3.4	4.5	
Reverse transfer capacitance	C <sub>rss</sub>		-	2.1	3.1	
Turn-on delay time	t <sub>d(on)</sub>		-	2.3	3.5	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =50 V, V <sub>GS</sub> =10 V,	-	3.2	4.6	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =0.19 A, $R_{\rm G,ext}$ =6 Ω	-	7.4	11.1	
Fall time	$t_{\mathrm{f}}$	]	-	22	33	
Gate Charge Characteristics				1		
Gate to source charge	Q <sub>gs</sub>	]	-	0.04	0.06	nC
Gate to drain charge	$Q_{gd}$	$V_{\rm DD}$ =50 V, $I_{\rm D}$ =0.19 A, $V_{\rm GS}$ =0 to 10 V	-	0.23	0.35	
Gate charge total	Qg		-	0.6	0.9	
Gate plateau voltage	V <sub>plateau</sub>		-	2.5	-	V
Reverse Diode						
Diode continous forward current	Is	T _25 °C	-	-	0.19	А
Diode pulse current	I <sub>S,pulse</sub>	- T <sub>A</sub> =25 °C	-	-	0.77	1
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =0.19 A, T <sub>j</sub> =25 °C	-	0.8	1.1	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =50 V, I <sub>F</sub> =0.19 A,	-	12	18	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i<sub>F</sub></i> /d <i>t</i> =100 A/μs	-	4.3	6.5	nC

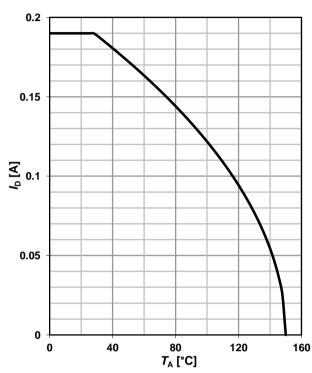


## 1 Power dissipation

## $P_{\text{tot}} = f(T_A)$

## 2 Drain current





## 3 Safe operating area

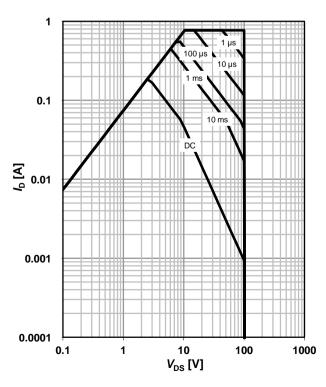
 $I_D=f(V_{DS}); T_A=25 \text{ °C}; D=0$ 

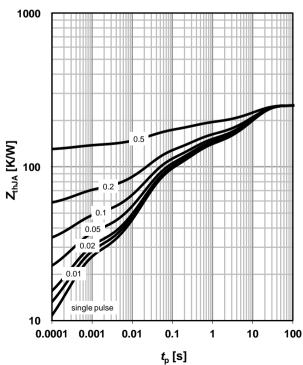
parameter:  $t_p$ 

# 4 Max. transient thermal impedance

 $Z_{\text{thJA}} = f(t_p)$ 

parameter:  $D=t_p/T$ 



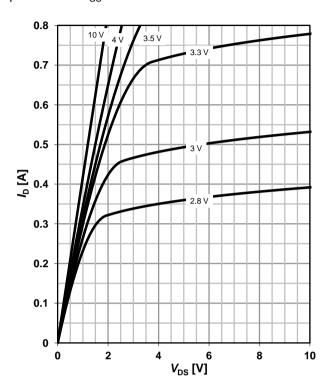




## 5 Typ. output characteristics

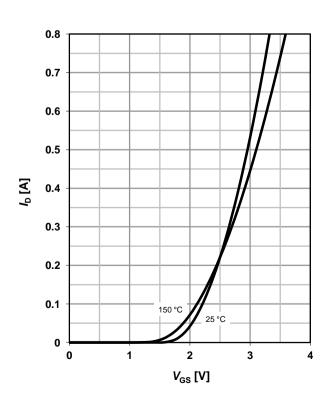
 $I_D=f(V_{DS}); T_j=25 °C$ 

parameter: V<sub>GS</sub>



# 7 Typ. transfer characteristics

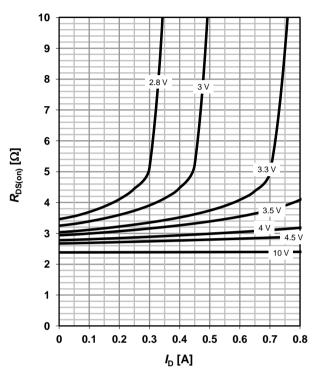
 $I_{D}=f(V_{GS}); |V_{DS}|>2|I_{D}|R_{DS(on)max}$ 



## 6 Typ. drain-source on resistance

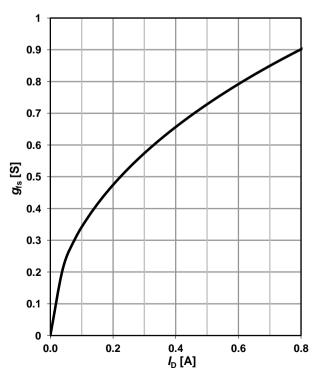
 $R_{DS(on)}=f(I_D); T_j=25 \text{ °C}$ 

parameter: V<sub>GS</sub>



## 8 Typ. forward transconductance

 $g_{fs}$ =f( $I_D$ );  $T_j$ =25 °C





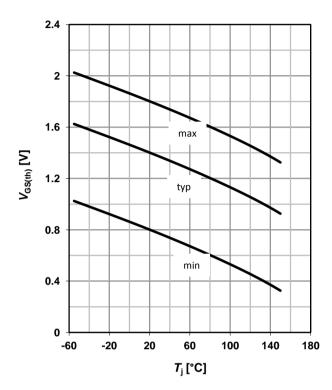
## 9 Drain-source on-state resistance

 $R_{DS(on)} = f(T_i); I_D = 0.19 \text{ A}; V_{GS} = 10 \text{ V}$ 

# 14 12 10 10 8 98% 6 4 2 98% 60 100 140 180 T<sub>j</sub> [°C]

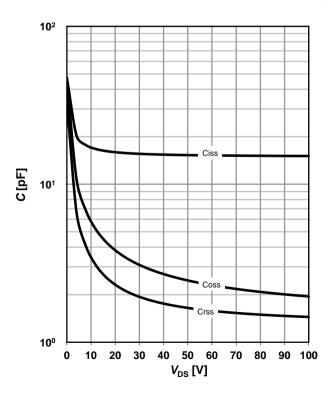
## 10 Typ. gate threshold voltage

 $V_{\text{GS(th)}} = f(T_j); V_{\text{DS}} = V_{\text{GS}}; I_{\text{D}} = 13 \,\mu\text{A}$  parameter:  $I_{\text{D}}$ 



## 11 Typ. capacitances

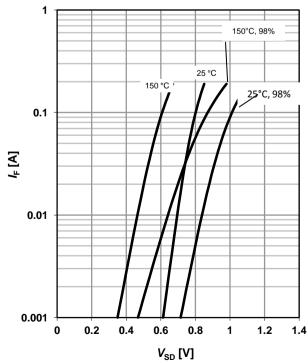
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz; T_i=25$ °C



## 12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$ 

parameter: T<sub>i</sub>

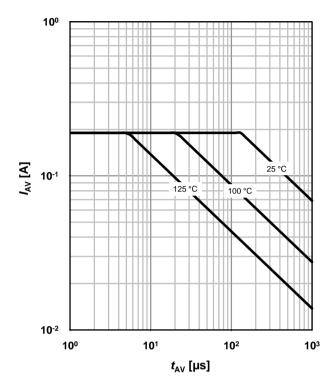




## 13 Avalanche characteristics

 $I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$ 

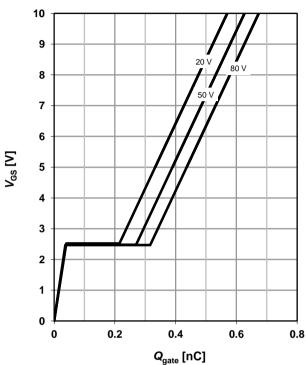
parameter:  $T_{j(start)}$ 



## 14 Typ. gate charge

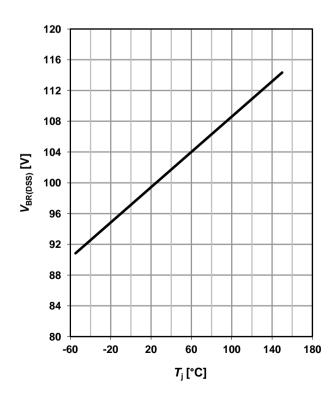
 $V_{GS}$ =f( $Q_{gate}$ );  $I_D$ =0.19 A pulsed

parameter:  $V_{\rm DD}$ 

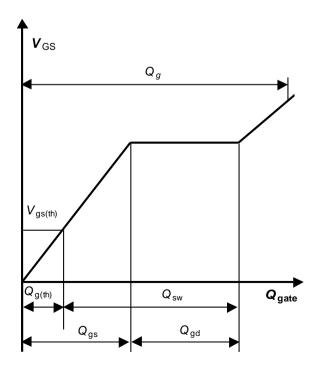


## 15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=250 \mu A$ 



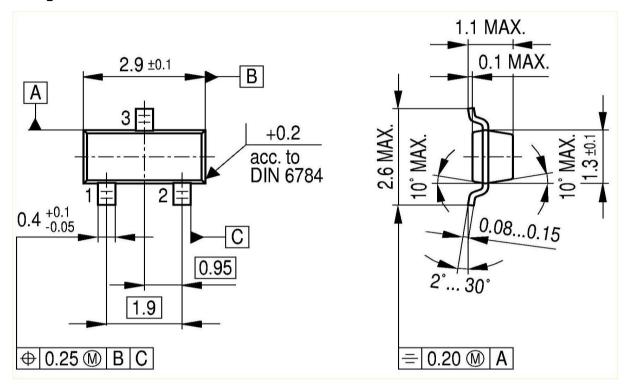
## 16 Gate charge waveforms



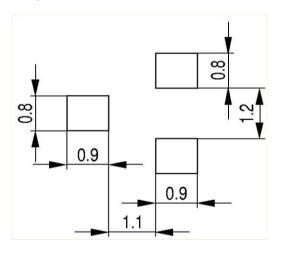


## SOT23

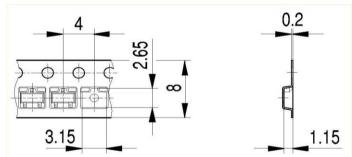
## Package Outline:



## **Footprint:**



## Packaging:



Dimensions in mm



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